## Notice of References Cited Application/Control No. 10/790,880 Applicant(s)/Patent Under Reexamination AKIYAMA ET AL. Examiner Denise Tran Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0193782	09-2004	Bordui, David	711/103
*	В	US-2004/0015646	01-2004	Kook et al.	711/5
*	С	US-6,704,835	03-2004	Garner, Richard P.	711/103
*	D	US-5,488,711	01-1996	Hewitt et al.	711/103
*	Ε	US-6,263,398	07-2001	Taylor et al.	711/3
*	F	US-2004/0027857	02-2004	Ooishi, Tsukasa	365/185.11
	G	US-			
	н	US-			
	ı	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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